

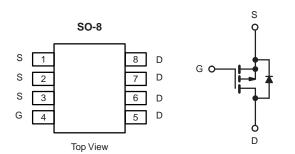
# NCE40P06S-VB Datasheet P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ ) Max.	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)		
- 40	0.0176 at V <sub>GS</sub> = - 10 V	- 8 <sup>d</sup>	35.4 nC		
- 40	$0.0208$ at $V_{GS} = -4.5 \text{ V}$	- 7 <sup>d</sup>	33.4 IIC		

### **FEATURES**

100% R<sub>g</sub> and UIS Tested





#### P-Channel MOSFET

### **APPLICATIONS**

- Adaptor Switch
- Load Switch
- Power Management
- Mobile Computing

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	- 40	- 1	
Gate-Source Voltage	$V_{GS}$	± 20	V	
	T <sub>C</sub> = 25 °C		- 8 <sup>d</sup>	
Continuous Drain Current (T. – 150 °C)	T <sub>C</sub> = 70 °C	1 , 🗀	-7 <sup>d</sup>	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	- 7.7 <sup>a, b</sup>	
	T <sub>A</sub> = 70 °C		- 7.7 <sup>a, b</sup>	
Pulsed Drain Current (t = 300 μs)	•	I <sub>DM</sub>	- 32	Α
Castinuas Cassas Daris Diada Cossast	T <sub>C</sub> = 25 °C		- 18 <sup>d</sup>	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	l <sub>s</sub>	- 3 <sup>a, b</sup>	
Avalanche Current	1 0411	I <sub>AS</sub>	- 20	
Single-Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	20	mJ
	T <sub>C</sub> = 25 °C		52	
Maximum Dawar Dissipation	T <sub>C</sub> = 70 °C	ь —	33	W
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.7 <sup>a, b</sup>	VV
	T <sub>A</sub> = 70 °C		2.4 <sup>a, b</sup>	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature)e, f		260		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	26	33	°C/W	
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	1.9	2.4	- °C/W	

# Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 81 °C/W.
- d. Package limited.

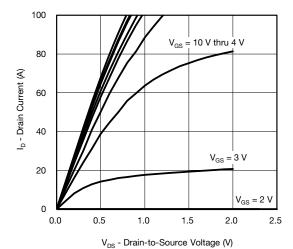


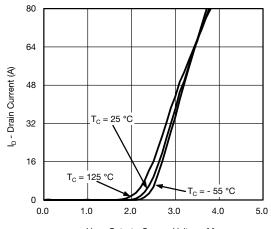
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 40			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 23		\//90	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η <sub>D</sub> = - 250 μΑ		4.6		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zara Cata Valtaga Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V		- 1			
Zero Gate Voltage Drain Current		V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5	μΑ	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
D : 0	D	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 15 A		0.0176	3		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 10 A		0.0208		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 15 A		50		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			3280		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		427			
Reverse Transfer Capacitance	C <sub>rss</sub>			382			
T. 10 . 0	$Q_g$ $V_{DS} = -$	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		73	110	- nC	
Total Gate Charge				35.4	53		
Gate-Source Charge	$Q_{gs}$	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		10.6		nC	
Gate-Drain Charge	$Q_{gd}$			11.6			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.4	1.6	3.2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			11	22		
Rise Time	t <sub>r</sub>	$V_{DD} = -15 \text{ V}, R_{L} = 1.5 \Omega$		11	22		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		45	90		
Fall Time	t <sub>f</sub>			8	16	no	
Turn-On Delay Time	t <sub>d(on)</sub>			55	100	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, $R_L$ = 1.5 $\Omega$		82	150		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		40	80		
Fall Time	t <sub>f</sub>			13	26		
<b>Drain-Source Body Diode Characterist</b>	ics						
Continous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 18	Α	
Pulse Diode Forward Current	I <sub>SM</sub>				- 70	_ ^	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 3 A, V <sub>GS</sub> = 0 V		- 0.74	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			18	36	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L = 40 A dl/dt = 400 A/up T 25 °C		8	16	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		7			
Reverse Recovery Rise Time	t <sub>b</sub>			11		ns	

a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$  b. Guaranteed by design, not subject to production testing.



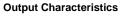
# TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

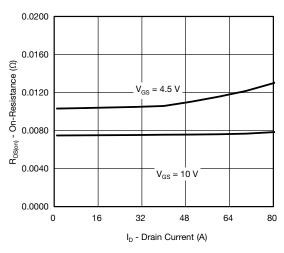




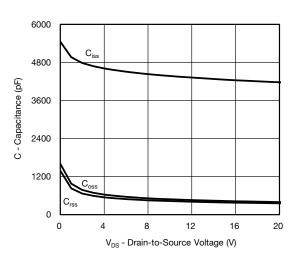
V<sub>GS</sub> - Gate-to-Source Voltage (V)

Transfer Characteristics

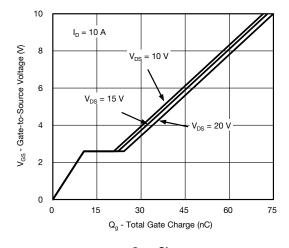




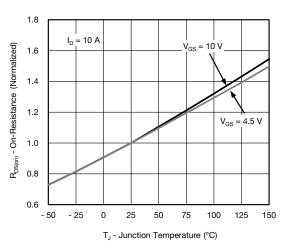
On-Resistance vs. Drain Current



Capacitance



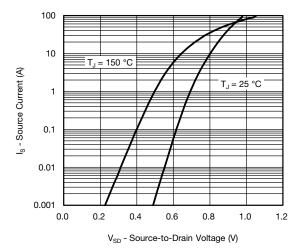
Gate Charge O



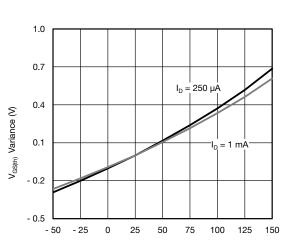
On-Resistance vs. Junction Temperature



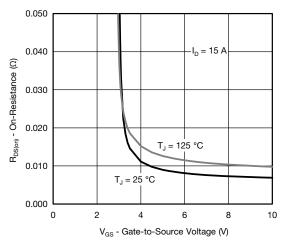
# TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



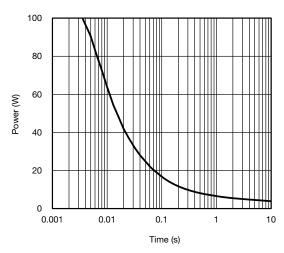
#### Source-Drain Diode Forward Voltage



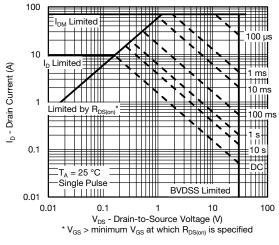
 $T_J$  - Temperature (°C) Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



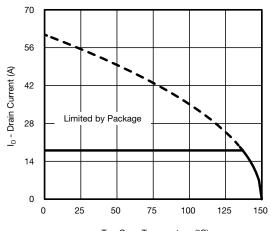
Single Pulse Power, Junction-to-Ambient



Safe Operating Area

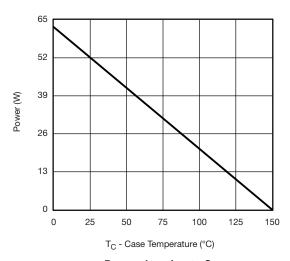


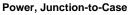
# MOSFET TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

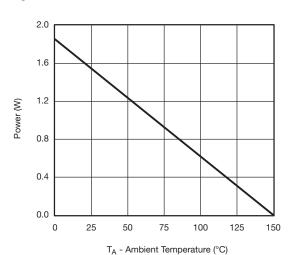


### $T_{\text{C}}$ - Case Temperature (°C)

### **Current Derating\***





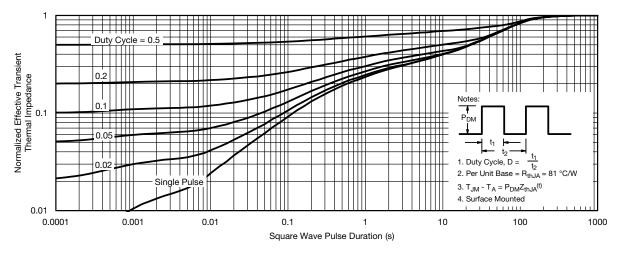


Power, Junction-to-Ambient

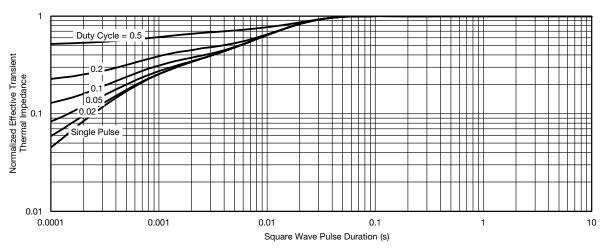
<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



# TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



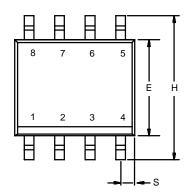
Normalized Thermal Transient Impedance, Junction-to-Ambient

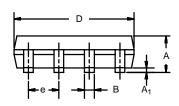


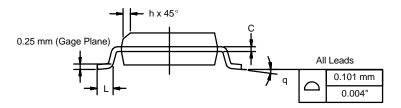
Normalized Thermal Transient Impedance, Junction-to-Case



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







	MILLIM	MILLIMETERS INCHES				
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A <sub>1</sub>	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
Е	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pey J. 11-Sep-06						

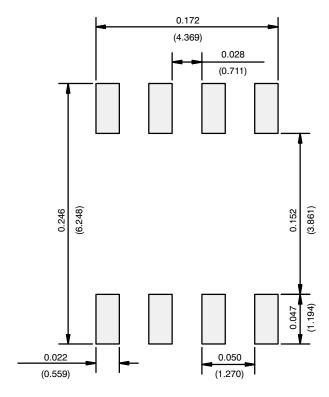
ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498

8



# **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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